Abstracts

A Miniature Magnetic Field Probe for Measuring Fields in Planar High-Frequency Circuits

Y. Gao and I. Wolff. "A Miniature Magnetic Field Probe for Measuring Fields in Planar High-Frequency Circuits." 1995 MTT-S International Microwave Symposium Digest 95.3 (1995 Vol. III [MWSYM]): 1159-1162.

A new non-contacting miniature magnetic field probe for measuring the surface current distribution on high-frequency planar circuits in the 5-20 GHz band has been designed, fabricated and tested. This field probe has a very small dimension and needs no connection to the operating circuit under test, therefore there is almost no perturbation on the circuit properties. This simple and practical magnetic field probe can be used to assist the design of microwave circuits and to test products in industry.

❑ Return to main document.

Click on title for a complete paper.